**Preferred Devices** 

# **Complementary Silicon Plastic Power Transistors**

# D<sup>2</sup>PAK for Surface Mount

- Lead Formed for Surface Mount Applications in Plastic Sleeves (No Suffix)
- Lead Formed Version in 16 mm Tape & Reel ("T4" Suffix)
- Electrically the Same as TIP41 and T1P42 Series

#### **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector–Emitter Voltage	V <sub>CEO</sub>	100	Vdc
Collector-Base Voltage	V <sub>CB</sub>	100	Vdc
Emitter–Base Voltage	V <sub>EB</sub>	5.0	Vdc
Collector Current – Continuous – Peak	I <sub>C</sub>	6.0 10	Adc
Base Current	I <sub>B</sub>	2.0	Adc
Total Power Dissipation @ T <sub>C</sub> = 25°C Derate above 25°C	P <sub>D</sub>	65 0.52	Watts W/°C
Total Power Dissipation @ T <sub>A</sub> = 25°C Derate above 25°C	P <sub>D</sub>	2.0 0.016	Watts W/°C
Unclamped Inductive Load Energy (Note 1.)	Е	62.5	mJ
Operating and Storage Junction Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-65 to +150	°C

#### THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	1.92	°C/W
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	62.5	°C/W
Thermal Resistance, Junction to Ambient (Note 2.)	$R_{\theta JA}$	50	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 10 Seconds	TL	260	°C

- 1.  $I_C$  = 2.5 A, L = 20 mH, P.R.F. = 10 Hz,  $V_{CC}$  = 10 V,  $R_{BE}$  = 100  $\Omega$
- When surface mounted to an FR-4 board using the minimum recommended pad size.



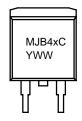
http://onsemi.com

# COMPLEMENTARY SILICON POWER TRANSISTORS 6 AMPERES 100 VOLTS 65 WATTS

#### **MARKING DIAGRAM**



D<sup>2</sup>PAK CASE 418B STYLE 1



MJB4xC = Specific Device Code

x = 1 or 2
 Y = Year
 WW = Work Week

# **ORDERING INFORMATION**

Device	Package	Shipping	
MJB41C	D <sup>2</sup> PAK	50 Units/Rail	
MJB41CT4	D <sup>2</sup> PAK	800/Tape & Reel	
MJB42C	D <sup>2</sup> PAK	50 Units/Rail	
MJB42CT4	D <sup>2</sup> PAK	800/Tape & Reel	

**Preferred** devices are recommended choices for future use and best overall value.

## **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector–Emitter Sustaining Voltage (Note 3.) (I <sub>C</sub> = 30 mAdc, I <sub>B</sub> = 0)	V <sub>CEO(sus)</sub>	100	_	Vdc
Collector Cutoff Current (V <sub>CE</sub> = 60 Vdc, I <sub>B</sub> = 0)	I <sub>CEO</sub>	_	0.7	mAdc
Collector Cutoff Current (V <sub>CE</sub> = 100 Vdc, V <sub>EB</sub> = 0)	I <sub>CES</sub>	-	100	μAdc
Emitter Cutoff Current ( $V_{BE} = 5.0 \text{ Vdc}$ , $I_{C} = 0$ )	I <sub>EBO</sub>	Ī	50	μAdc
ON CHARACTERISTICS (Note 3.)				
DC Current Gain ( $I_C = 0.3$ Adc, $V_{CE} = 4.0$ Vdc) ( $I_C = 3.0$ Adc, $V_{CE} = 4.0$ Vdc)	h <sub>FE</sub>	30 15	- 75	_
Collector–Emitter Saturation Voltage (I <sub>C</sub> = 6.0 Adc, I <sub>B</sub> = 600 mAdc)	V <sub>CE(sat)</sub>	-	1.5	Vdc
Base–Emitter On Voltage (I <sub>C</sub> = 6.0 Adc, V <sub>CE</sub> = 4.0 Vdc)	V <sub>BE(on)</sub>	1	2.0	Vdc
DYNAMIC CHARACTERISTICS				
Current–Gain – Bandwidth Product ( $I_C = 500 \text{ mAdc}$ , $V_{CE} = 10 \text{ Vdc}$ , $f_{test} = 1.0 \text{ MHz}$ )	f <sub>T</sub>	3.0	_	MHz
Small–Signal Current Gain (I <sub>C</sub> = 0.5 Adc, V <sub>CE</sub> = 10 Vdc, f = 1.0 kHz)	h <sub>fe</sub>	20	_	_

<sup>3.</sup> Pulse Test: Pulse Width  $\leq 300 \,\mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ .

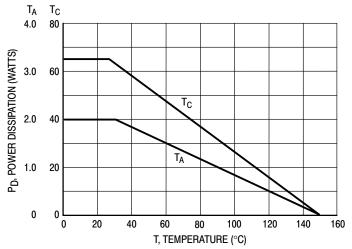
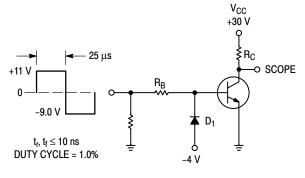


Figure 1. Power Derating



 $R_B$  and  $R_C$  VARIED TO OBTAIN DESIRED CURRENT LEVELS D1 MUST BE FAST RECOVERY TYPE, e.g.: 1N5825 USED ABOVE  $I_B\approx 100$  mA MSD6100 USED BELOW  $I_B\approx 100$  mA

Figure 2. Switching Time Test Circuit

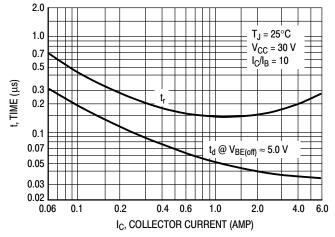


Figure 3. Turn-On Time

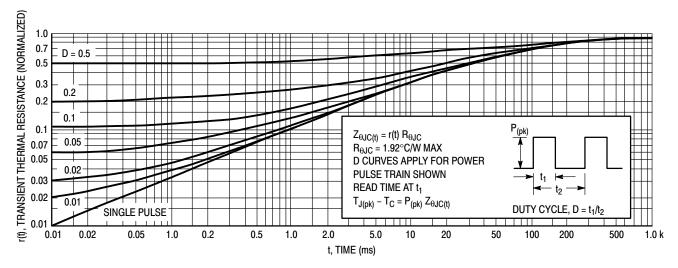


Figure 4. Thermal Response

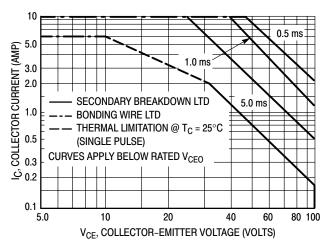


Figure 5. Active-Region Safe Operating Area

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate  $I_C - V_{CE}$  limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 5 is based on  $T_{J(pk)} = 150^{\circ}\text{C}$ ;  $T_{C}$  is variable depending on conditions. Second breakdown pulse limits are valid for duty cycles to 10% provided  $T_{J(pk)} \leq 150^{\circ}\text{C}$ .  $T_{J(pk)}$  may be calculated from the data in Figure 4. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

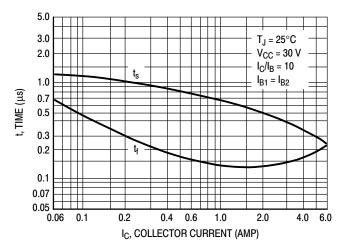


Figure 6. Turn-Off Time

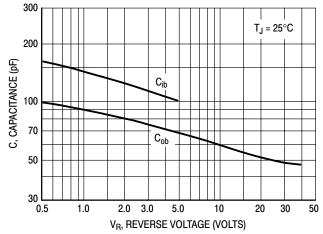


Figure 7. Capacitance

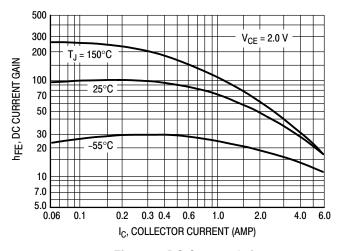


Figure 8. DC Current Gain

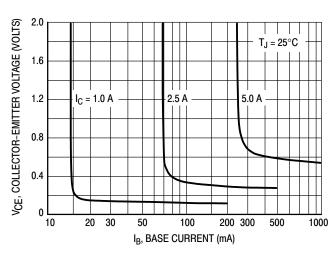


Figure 9. Collector Saturation Region

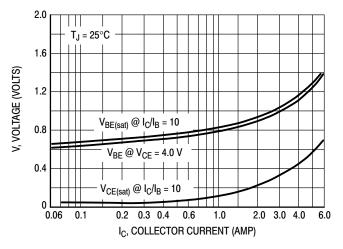
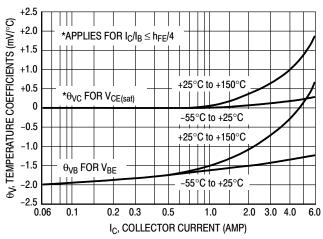


Figure 10. "On" Voltages



**Figure 11. Temperature Coefficients** 

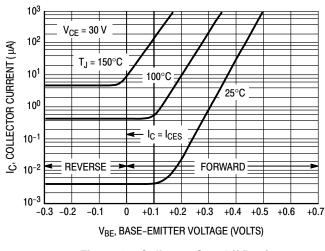


Figure 12. Collector Cut-Off Region

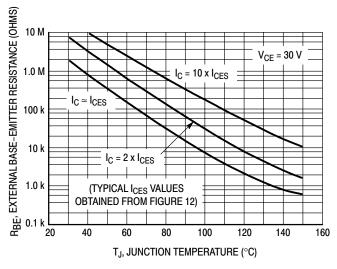


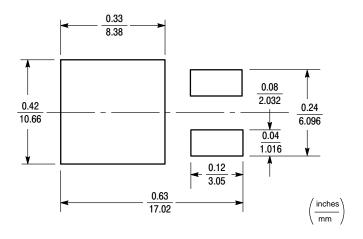
Figure 13. Effects of Base-Emitter Resistance

# INFORMATION FOR USING THE D2PAK SURFACE MOUNT PACKAGE

## RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to ensure proper solder connection

interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



## POWER DISSIPATION FOR A SURFACE MOUNT DEVICE

The power dissipation for a surface mount device is a function of the Collector pad size. These can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by  $T_{J(max)}$ , the maximum rated junction temperature of the die,  $R_{\theta JA}$ , the thermal resistance from the device junction to ambient, and the operating temperature,  $T_A$ . Using the values provided on the data sheet,  $P_D$  can be calculated as follows:

$$P_{D} = \frac{T_{J(max)} - T_{A}}{R_{\theta JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature  $T_A$  of 25°C, one can calculate the power dissipation of the device. For a  $D^2PAK$  device,  $P_D$  is calculated as follows.

$$P_D = \frac{150^{\circ}C - 25^{\circ}C}{50^{\circ}C/W} = 2.5 \text{ Watts}$$

The 50°C/W for the D<sup>2</sup>PAK package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 2.5 Watts. There are other alternatives to achieving higher power dissipation from the surface mount packages. One is to increase the area of the Collector pad. By increasing the area of the collection pad, the power dissipation can be increased.

Although one can almost double the power dissipation with this method, one will be giving up area on the printed circuit board which can defeat the purpose of using surface mount technology. For example, a graph of  $R_{\theta JA}$  versus Collector pad area is shown in Figure 14.

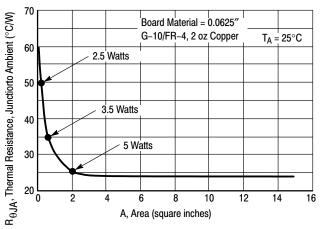


Figure 14. Thermal Resistance versus Collector Pad Area for the D<sup>2</sup>PAK Package (Typical)

Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad<sup>®</sup>. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

#### **SOLDER STENCIL GUIDELINES**

Prior to placing surface mount components onto a printed circuit board, solder paste must be applied to the pads. Solder stencils are used to screen the optimum amount. These stencils are typically 0.008 inches thick and may be made of brass or stainless steel. For packages such as the SC–59, SC–70/SOT–323, SOD–123, SOT–23, SOT–143, SOT–223, SO–8, SO–14, SO–16, and SMB/SMC diode packages, the stencil opening should be the same as the pad size or a 1:1 registration. This is not the case with the DPAK and D<sup>2</sup>PAK packages. If one uses a 1:1 opening to screen solder onto the Collector pad, misalignment and/or "tombstoning" may occur due to an excess of solder. For these two packages, the opening in the stencil for the paste should be approximately 50% of the tab area. The opening for the leads is still a 1:1 registration. Figure 15. shows a

typical stencil for the DPAK and D<sup>2</sup>PAK packages. The pattern of the opening in the stencil for the Collector pad is not critical as long as it allows approximately 50% of the pad to be covered with paste.

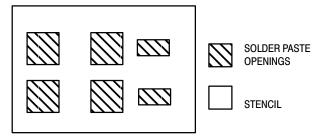


Figure 15. Typical Stencil for DPAK and D<sup>2</sup>PAK Packages

#### **SOLDERING PRECAUTIONS**

The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.\*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.

- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes.
   Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.
- \* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.
- \* Due to shadowing and the inability to set the wave height to incorporate other surface mount components, the D<sup>2</sup>PAK is not recommended for wave soldering.

#### TYPICAL SOLDER HEATING PROFILE

For any given circuit board, there will be a group of control settings that will give the desired heat pattern. The operator must set temperatures for several heating zones, and a figure for belt speed. Taken together, these control settings make up a heating "profile" for that particular circuit board. On machines controlled by a computer, the computer remembers these profiles from one operating session to the next. Figure 16. shows a typical heating profile for use when soldering a surface mount device to a printed circuit board. This profile will vary among soldering systems but it is a good starting point. Factors that can affect the profile include the type of soldering system in use, density and types of components on the board, type of solder used, and the type of board or substrate material being used. This profile shows temperature versus time.

The line on the graph shows the actual temperature that might be experienced on the surface of a test board at or near a central solder joint. The two profiles are based on a high density and a low density board. The Vitronics SMD310 convection/infrared reflow soldering system was used to generate this profile. The type of solder used was 62/36/2 Tin Lead Silver with a melting point between 177–189°C. When this type of furnace is used for solder reflow work, the circuit boards and solder joints tend to heat first. The components on the board are then heated by conduction. The circuit board, because it has a large surface area, absorbs the thermal energy more efficiently, then distributes this energy to the components. Because of this effect, the main body of a component may be up to 30 degrees cooler than the adjacent solder joints.

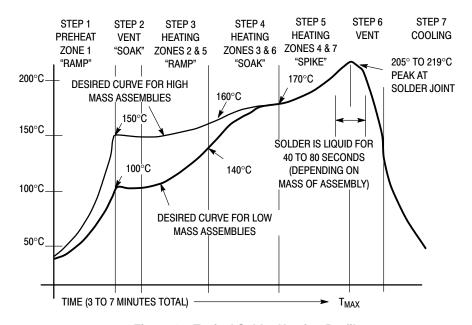
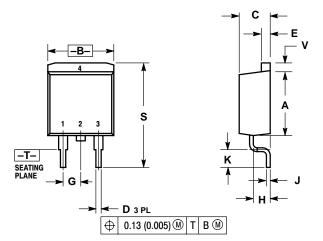


Figure 16. Typical Solder Heating Profile

#### PACKAGE DIMENSIONS

#### D<sup>2</sup>PAK

CASE 418B-03 ISSUE D



#### NOTES

- 1. DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.340	0.380	8.64	9.65
В	0.380	0.405	9.65	10.29
С	0.160	0.190	4.06	4.83
D	0.020	0.035	0.51	0.89
E	0.045	0.055	1.14	1.40
G	0.100 BSC		2.54 BSC	
Н	0.080	0.110	2.03	2.79
J	0.018	0.025	0.46	0.64
K	0.090	0.110	2.29	2.79
S	0.575	0.625	14.60	15.88
٧	0.045	0.055	1.14	1.40

STYLE 1:

PIN 1 BASE

- 2. COLLECTOR 3. EMITTER 4. COLLECTOR

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